

Helms, H. *Operational Amplifiers 1987 Source Book*. Englewood Cliffs, NJ: Prentice Hall, Inc., 1987.

DIGITAL CIRCUITS AND DEVICES

- CMOS/NMOS Integrated Circuits*, RCA Solid State, 1980.
- DeMassa, T. A.; and Z. Ciccone. *Digital Integrated Circuits*. New York: John Wiley and Sons, Inc., 1996.
- Glasford, G. M. *Digital Electronic Circuits*. Englewood Cliffs, NJ: Prentice Hall, Inc., 1988.
- Hauser, J. R., "Noise Margin Criteria for Digital Logic Circuits." *IEEE Transactions on Education* 36, No. 4 (November 1993), pp. 363-68.
- Hodges, D. A.; and H. G. Jackson. *Analysis and Design of Digital Integrated Circuits*. New York: McGraw-Hill Book Co., 1983.
- Kang, S.-M.; and Y. Leblebici. *CMOS Digital Integrated Circuits: Analysis and Design*. 2nd ed. Boston: WCB/McGraw-Hill, 1999.
- Lohstroh, J. "Static and Dynamic Noise Margins of Logic Circuits," *IEEE Journal of Solid-State Circuits* SC-14, No. 3 (June 1979), pp. 591-98.
- Mead, C.; and L. Conway. *Introduction to VLSI Systems*. Reading, MA: Addison-Wesley Publishing Co., Inc., 1980.
- Mukherjee, A. *Introduction to nMOS and CMOS VLSI Systems Design*. Englewood Cliffs, NJ: Prentice Hall, Inc., 1986.
- Prince, B. *Semiconductor Memories; A Handbook of Design, Manufacture and Applications*. 2nd ed. New York: John Wiley and Sons, Inc., 1991.
- Wang, N. *Digital MOS Integrated Circuits*. Englewood Cliffs, NJ: Prentice Hall, Inc., 1989.
- Wilson, G. R. "Advances in Bipolar VLSI." *Proceedings of the IEEE* 78, No. 11 (November 1990), pp. 1707-19.

SPICE AND PSPICE REFERENCES

- Banzhaf, W. *Computer-Aided Circuit Analysis Using PSpice*. 2nd ed. Englewood Cliffs, NJ: Prentice Hall, Inc., 1992.
- Brown, W. L.; and A. Y. J. Szeto. "Verifying Spice Results with Hand Calculations: Handling Common Discrepancies." *IEEE Transactions on Education*, 37, No. 4 (November 1994), pp. 358-68.
- Goody, R. W. *MicroSim PSpice for Windows: Volume I: DC, AC, and Devices and Circuits*. 2nd ed. Upper Saddle River, NJ: Prentice-Hall, Inc., 1998.
- Goody, R. W. *MicroSim PSpice for Windows: Volume II: Operational Amplifiers and Digital Circuits*. 2nd ed. Upper Saddle River, NJ: Prentice-Hall, 1998.
- Herniter, M. E. *Schematic Capture with MicroSim PSpice*. 3rd ed. Upper Saddle River, NJ: Prentice-Hall, 1998.
- Meares, L. G.; and C. E. Hymowitz. *Simulating with Spice*. San Pedro, CA: Intusoft, 1988.
- MicroSim Staff. *PSpice User's Manual Version 4.03*. Irvine, CA: MicroSim Corporation, 1990.
- Natarajan, S. "An Effective Approach to Obtain Model Parameters for BJTs and FETs from Data Books." *IEEE Transactions on Education* 35, No. 2 (May 1992), pp. 164-69.

- Rashid, M. H. *SPICE for Circuits and Electronics Using PSpice*. Englewood Cliffs, NJ: Prentice Hall, Inc., 1990.
- Roberts, G. W.; and A. S. Sedra. *SPICE for Microelectronic Circuits*. 3rd ed. New York: Saunders College Publishing, 1992.
- Thorpe, T. W. *Computerized Circuit Analysis with SPICE*. New York: John Wiley and Sons, Inc., 1992.
- Tuinenga, P. W. *SPICE: A Guide to Circuit Simulation and Analysis Using PSpice*. 2nd ed. Englewood Cliffs, NJ: Prentice Hall, Inc., 1992.

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Answers to Selected Problems

Chapter 1

- 1.1 (a) (i) $1.9 \times 10^9 \text{ cm}^{-3}$,
 (ii) $8.71 \times 10^{10} \text{ cm}^{-3}$
 (b) (i) $1.34 \times 10^5 \text{ cm}^{-3}$,
 (ii) $1.63 \times 10^7 \text{ cm}^{-3}$
- 1.3 (a) n-type; $n_o = 5 \times 10^{15} \text{ cm}^{-3}$,
 $p_o = 4.5 \times 10^4 \text{ cm}^{-3}$
 (b) n-type; $n_o = 5 \times 10^{15} \text{ cm}^{-3}$,
 $p_o = 6.48 \times 10^{-4} \text{ cm}^{-3}$
- 1.6 (a) Add donors, $N_d = 7 \times 10^{15} \text{ cm}^{-3}$,
 (b) $T = 324 \text{ K}$
- 1.10 (a) $p_o = 10^{17} \text{ cm}^{-3}$, $n_o = 3.24 \times 10^{-5} \text{ cm}^{-3}$,
 (b) $n = n_o + \delta n \cong 10^{15} \text{ cm}^{-3}$; $p = p_o + \delta p = 1.01 \times 10^{17} \text{ cm}^{-3}$
- 1.13 For $N_d = 10^{16} \text{ cm}^{-3}$ and $N_a = 10^{15} \text{ cm}^{-3}$,
 $V_{bi} = 0.637 \text{ V}$; For $N_d = 10^{16} \text{ cm}^{-3}$ and
 $N_a = 10^{18} \text{ cm}^{-3}$, $V_{bi} = 0.817 \text{ V}$
- 1.17 (a) $f_o = 8.38 \text{ MHz}$;
 (b) $f_o = 13.2 \text{ MHz}$
- 1.20 (a) 0.430 V ; (b) 0.549 V
- 1.23 2.83×10^3
- 1.25 (a) $I_D = 0.145 \mu\text{A}$, $V_D = 0.046 \text{ V}$
 (b) $I_D = -30 \text{ nA}$, $V_D = -1.2 \text{ V}$
- 1.27 $V_I = 1.81 \text{ V}$
- 1.29 (a) $I_D = 0.0267 \text{ mA}$, $V_D = 0.7 \text{ V}$
 (b) $V_D = 0.45 \text{ V}$, $I_D = 0$
- 1.32 $I_{D1} = 0.65 \text{ mA}$, $I_{D2} = 1.30 \text{ mA}$,
 $R_I = 2.35 \text{ k}\Omega$

- 1.35 (a) and (b) $v_d = 1.30 \text{ mV}$ (peak-to-peak)

1.37 0.599 V; 0.299 V

- 1.41 (a) $V_O = 5.685 \text{ V}$,
 (b) $\Delta V_O = 0.039 \text{ V}$,
 (c) $V_O = 5.658 \text{ V}$

- 1.43 (a) 6.921 V; (b) -0.13 V

Chapter 2

- 2.4 (a) 6.06, (b) 1.58; PIV = 25.7 V for
 (a), PIV = 100.7 V for (b)
- 2.8 $R = 1.19 \Omega$, 32.25%, 18 W
- 2.11 3.04 V
- 2.13 (a) $I_L = 26.3 \text{ mA}$, $I_I = 45.0 \text{ mA}$,
 $I_Z = 18.8 \text{ mA}$
 (b) $R_L = 2 \text{ k}\Omega$
 (c) $R_L = 585 \Omega$
- 2.15 (a) $\Delta V_O = 0.815 \text{ V}$, (b) 4.08%
- 2.18 $R_i = 18.2 \Omega$, $C = 9900 \mu\text{F}$
- 2.21 (a) $v_O = v_I$ for $0 \leq v_I \leq 5.7 \text{ V}$;
 $v_O = \frac{v_I}{2.5} + 3.42$ for $5.7 \leq v_I \leq 15 \text{ V}$
 (b) $i_D = 0$ for $0 \leq v_I \leq 5.7 \text{ V}$;
 $i_D = \frac{0.6v_I - 3.42}{1 \text{ k}\Omega}$ for
 $5.7 \leq v_I \leq 15 \text{ V}$
- 2.33 (a) $I = I_{D1} = I_{D2} = 0$, $V_O = 10 \text{ V}$
 (b) $I_{D1} = 0$, $I = I_{D2} = 0.94 \text{ mA}$,
 $V_O = 1.07 \text{ V}$

- (c) $I_{D1} = 0$, $I = I_{D2} = 0.44$ mA,
 $V_O = 5.82$ V
(d) $I = 0.964$ mA,
 $I_{D1} = I_{D2} = 0.482$ mA,
 $V_O = 0.842$ V
- 2.35 (a) $V_1 = 6.9$ V, $V_2 = -0.6$ V,
 $I_{D1} = 1.25$ mA, $I_{D2} = 0$,
 $I_{D3} = 0.95$ mA
(b) $V_1 = 4.4$ V, $V_2 = -0.3$ V,
 $I_{D1} = 0.833$ mA,
 $I_{D2} = 0.107$ mA, $I_{D3} = 0$
(c) $V_1 = 4.4$ V, $V_2 = -0.6$ V,
 $R_1 = 10$ k Ω , $R_2 = 5$ k Ω ,
 $R_3 = 2.93$ k Ω
- 2.38 (a) $I_{D1} = 0.86$ mA, $V_O = 0$;
(b) $I_D = 0$, $V_O = -3.57$ V
- 2.40 (a) $I_D = 0$, $V_D = -2.5$ V;
(b) $I_D = 0.19$ mA, $V_D = 0.6$ V
- 2.43 (a) $V_{O1} = V_{O2} = 5$ V;
(b) $V_{O1} = 0.6$ V, $V_{O2} = 1.2$ V;
(c) $V_{O1} = 0.6$ V, $V_{O2} = 1.2$ V
- 2.47 $V_{PS} = 2.6$ V
- 3.28 3.97 V
- 3.31 $R_1 = 338$ k Ω , $R_2 = 58.7$ k Ω , $R_C = 6.49$ k Ω
- 3.34 (a) $I_{BQ} = 0.0624$ mA, $I_{CQ} = 4.68$ mA,
 $V_{CEQ} = 5.22$ V,
(b) $I_{BQ} = 0.0326$ mA, $I_{CQ} = 4.89$ mA,
 $V_{CEQ} = 4.41$ V
- 3.37 $I_{CQ} = 4.41$ mA, $V_{ECQ} = 6$ V, $R_C = 1.26$ k Ω
- 3.40 $I_{CQ} = 2.73$ mA, $V_{CEQ} = 6$ V,
 $R_1 = 23.2$ k Ω , $R_2 = 2.83$ k Ω
- 3.43 (a) $I_{BQ} = 0.0214$ mA, $I_{CQ} = 1.60$ mA,
 $V_{ECQ} = 15.2$ V,
(b) $I_{BQ} = 0.0161$ mA, $I_{CQ} = 1.61$ mA,
 $V_{ECQ} = 15.1$ V
- 3.46 $R_E = 4.90$ k Ω , $R_1 = 72.4$ k Ω ,
 $R_2 = 50.9$ k Ω , designed using $\beta = 60$.
- 3.49 (a) $R_{TH} = 6.67$ k Ω , $V_{TH} = 1.67$ V,
(b) $I_{BQ} = 0.593$ mA, $I_{CQ} = 3.56$ mA,
 $V_E = 2.76$ V, $V_C = -2.17$ V
- 3.52 (a) $R_{TH} = 54.7$ k Ω , $V_{TH} = -3.03$ V,
(b) $I_{CQ} = 0.227$ mA, $V_{CEQ} = 7.51$ V
- 3.55 $I_{E2} = 3.6$ mA, $I_{B2} = 0.0444$ mA,
 $I_{C2} = 3.56$ mA, $I_{E1} = 0.259$ mA,
 $I_{B1} = 0.0032$ mA, $I_{C1} = 0.256$ mA

Chapter 3

- 3.1 (a) $\beta_F = 85$, $\alpha_F = 0.9884$,
 $i_E = 516 \mu\text{A}$
(b) $\beta_F = 53$, $\alpha_F + 0.9815$,
 $i_E = 2.70$ mA
- 3.4 $i_C = 1.85$ mA, $i_B = 0.0154$ mA,
 $i_E = 1.865$ mA
- 3.7 $I_{S1} = 1.69 \times 10^{-13}$ A, $I_{S2} = 6.94 \times 10^{-15}$ A,
 $I_{S1}/I_{S2} = 24.35$
- 3.10 60.6
- 3.14 $R_B = 120$ k Ω , $I_{CQ} = 1.05$ mA,
 $R_C = 2.38$ k Ω
- 3.16 (a) $I_E = 0$, $V_C = 6$ V,
(b) $I_E = 0.3$ mA, $V_C = 3$ V,
(c) $I_E = 1.3$ mA, $V_C = 1.5$ V
- 3.19 $V_B = 1.19$ V, $I_E = 0.49$ mA
- 3.22 $V_E = -0.7$ V, $V_C = 2.84$ V
- 3.25 $I_{E1} = I_{E2} = 0.5$ mA, $V_{C1} = V_{C2} = 3$ V

Chapter 4

- 4.1 (a) $g_m = 76.9$ mA/V, $r_\pi = 2.34$ k Ω ,
 $r_o = 75$ k Ω ,
(b) $g_m = 19.2$ mA/V, $r_\pi = 9.36$ k Ω ,
 $r_o = 300$ k Ω
- 4.4 $41.5 \leq g_m \leq 50.8$ mA/V,
 $1.58 \leq r_\pi \leq 2.89$ k Ω
- 4.7 (a) $V_B = -0.0347$ V, $V_E = -0.735$ V,
(b) $R_C = 6.43$ k Ω , (c) $A_V = -83.7$,
(d) $A_V = -74.9$
- 4.10 (a) $I_{CQ} = 1.19$ mA, $V_{ECQ} = 8.42$ V,
(b) $A_V = -1.94$,
(c) $1.76 \leq |A_V| \leq 2.14$
- 4.13 (a) $R_E = 11.0$ k Ω , (b) $R_C = 3.71$ k Ω ,
(c) $A_V = -43.9$, (d) $R_i = 4.81$ k Ω
- 4.16 (a) $39.0 \leq |A_V| \leq 43.2$,

- (b) $1.64 \leq R_i \leq 2.13 \text{ k}\Omega$,
 (c) $3.70 \leq R_o \leq 3.85 \text{ k}\Omega$

4.19 $r_e = r_\pi \left| \left(\frac{1}{g_m} \right) \right| r_o$

4.25 3.24 V peak-to-peak

4.28 0.342 mA peak-to-peak

4.31 Δi_C (peak-to-peak) = 1.29 mA,
 Δv_{CE} (peak-to-peak) = 2.58 V

4.33 (a) $I_{CQ} = 2.09 \text{ mA}$, $V_{CEQ} = 3.69 \text{ V}$,
 (c) $A_V = 0.988$,
 (d) $R_{ib} = 122 \text{ k}\Omega$, $R_o = 12.2 \Omega$

4.37 (a) $I_{CQ} = 0.650 \text{ mA}$, $V_{ECQ} = 3.01 \text{ V}$,
 (c) $A_V = 0.977$, $A_i = 4.61$,
 (d) $R_{ib} = 88.2 \text{ k}\Omega$, $R_o = 38.7 \Omega$,
 (e) $4.21 \leq A_i \leq 5.05$

4.40 (a) $V_B = 0.0617 \text{ V}$, $V_E = 0.762 \text{ V}$;
 (b) $g_m = 19 \text{ mA/V}$, $r_\pi = 4.21 \text{ k}\Omega$,
 $r_o = 304 \text{ k}\Omega$;
 (c) $A_v = 0.906$,
 $A_i = 14.8$; (d) $A_v = 0.728$,
 $A_i = 14.8$

4.44 (a) $I_{CQ} = 1.46 \text{ mA}$, $V_{CEQ} = 7.75 \text{ V}$;
 (b) $R_m = 1.93 \text{ k}\Omega$; (c) $A_v = 26.0$

4.47 (a) $V_E = 0.5 \text{ V}$, $V_B = 1.20 \text{ V}$,
 $V_C = 1.70 \text{ V}$,
 (b) $A_V = 9.36$, (c) $R_i = 49.5 \Omega$

4.50 (a) $g_{m1} = 42.7 \text{ mA/V}$, $r_{\pi 1} = 2.34 \text{ k}\Omega$,
 $g_{m2} = 48.5 \text{ mA/V}$, $r_{\pi 2} = 2.06 \text{ k}\Omega$,
 $r_{o1} = r_{o2} = \infty$,
 (b) $A_{V1} = -85.4$, $A_{V2} = -97$,
 (c) $A_V = 3890$

4.53 (a) $I_{C1} = 12.8 \mu\text{A}$, $V_{CE1} = 5.11 \text{ V}$,
 $I_{C2} = 1.29 \text{ mA}$, $V_{CE2} = 5.81 \text{ V}$,
 (b) $A_V = -55.2$,
 (c) $R_{ib} = 74.4 \text{ k}\Omega$, $R_o = 2.2 \text{ k}\Omega$

4.56 (a) $P_{RE} = 1.66 \text{ mW}$, $P_{RC} = 13.0 \text{ mW}$,
 $P_Q = 7.0 \text{ mW}$,
 (b) $\bar{P}_{RL} = 1.44 \text{ mW}$

4.59 (a) $P_{RC} = 7.02 \text{ mW}$, $P_Q = 2.65 \text{ mW}$,

- (b) $\bar{P}_{RL} = 0.290 \text{ mW}$,
 $\bar{P}_{RC} = 0.0289 \text{ mW}$, $\bar{P}_Q = 2.33 \text{ mW}$

Chapter 5

5.1 (a) 3.06 mA, (b) 2.81 mA

5.4 $W/L = 9.375$

5.7 7.21 μm

5.10 (a) $V_{SD(\text{sat})} = 1 \text{ V}$, $I_D = 0.12 \text{ mA}$
 (b) $V_{SD(\text{sat})} = 2 \text{ V}$, $I_D = 0.48 \text{ mA}$
 (c) $V_{SD(\text{sat})} = 3 \text{ V}$, $I_D = 1.08 \text{ mA}$

5.13 781 $\text{k}\Omega$, 63.7 $\text{k}\Omega$, 100 V

5.16 $1.24 \text{ V}^{1/2}$

5.19 $V_{GS} = 2.05 \text{ V}$, $I_D = 0.775 \text{ mA}$,
 $V_{DS} = 5.35 \text{ V}$

5.22 $V_S = 2.21 \text{ V}$, $V_{SD} = 5.21 \text{ V}$

5.25 For example, let $W/L = 10$, then
 $V_{SG} = 4 \text{ V}$, $R_S = 5 \text{ k}\Omega$, $R_D = 7.5 \text{ k}\Omega$,
 $R_1 = 100 \text{ k}\Omega$, $R_2 = 150 \text{ k}\Omega$

5.28 $R_D = 5 \text{ k}\Omega$, $R_S = 2.36 \text{ k}\Omega$

5.31 $R_D = 4 \text{ k}\Omega$. Let $W/L = 10$, then
 $R_S = 3.94 \text{ k}\Omega$

5.34 $(W/L)_I = 3.23$

5.37 20.3

5.40 $I_D = 0.49 \text{ mA}$, $W/L = 0.731$

5.43 $V_{DS} > V_{DS(\text{sat})} = -V_P$, $I_D = I_{DSS}$

5.46 $V_{DD} \leq -2.5 \text{ V}$, $V_S = -1.06 \text{ V}$

5.49 $V_{GSQ} = -1.17 \text{ V}$, $I_{DQ} = 5.85 \text{ mA}$,
 $V_{DSQ} = 7.13 \text{ V}$

5.52 $R_D = 0.9 \text{ k}\Omega$, $R_1 = 8.6 \text{ k}\Omega$,
 $R_2 = 91.4 \text{ k}\Omega$

5.55 $R_D = 1.75 \text{ k}\Omega$, $I_D = I_{DSS} = 4 \text{ mA}$

5.58 $128 \mu\text{A/V}^2$

Chapter 6

6.1 (a) 12.5, (b) 2.21 V

6.4 0.833 mA

- 6.6 (a) $R_D = 8 \text{ k}\Omega$, $W/L = 11.6$,
 (b) $g_m = 0.835 \text{ mA/V}$, $r_o = 133 \text{ k}\Omega$,
 (c) -6.3
- 6.10 2.1 mA/V
- 6.13 (b) -2.88 , (c) 2.76 V peak-to-peak
- 6.16 (a) $R_S = 0.5 \text{ k}\Omega$, $I_{DQ} = 1.0 \text{ mA}$,
 (b) -1.33
- 6.19 $K_n = 0.202 \text{ mA/V}^2$, $V_{TN} = -2.65 \text{ V}$,
 $R_D = 1.23 \text{ k}\Omega$, $R_S = 0.10 \text{ k}\Omega$,
 $R_1 = 529 \text{ k}\Omega$, $R_2 = 123 \text{ k}\Omega$
- 6.23 (No load) $A_V = 0.995$, $R_o = 0.249 \text{ k}\Omega$;
 (With load) $A_V = 0.905$, $R_o = 0.226 \text{ k}\Omega$
- 6.26 (a) 47.0 , (b) 3.13 mA
- 6.30 (a) 100Ω , (b) 100Ω
- 6.33 (a) $I_{DQ} = 0.365 \text{ mA}$, $V_{DSQ} = 4.53 \text{ V}$,
 (b) $g_m = 2.09 \text{ mA/V}$, $r_o = \infty$,
 (c) $A_V = 4.64$
- 6.36 (a) $R_S = 2.26 \text{ k}\Omega$, $R_D = 1.07 \text{ k}\Omega$,
 (b) $A_V = 4.74$
- 6.39 $0.936 \text{ k}\Omega$
- 6.42 (a) 0.731 , (b) $0.40 \text{ k}\Omega$
- 6.45 (a) $R_1 = 545 \text{ k}\Omega$, $R_2 = 1.50 \text{ M}\Omega$,
 (b) $I_{DQ1} = 0.269 \text{ mA}$, $I_{DQ2} = 0.5 \text{ mA}$,
 $V_{DSQ1} = 4.62 \text{ V}$,
 (c) $A_V = 0.714$, $R_o = 1.25 \text{ k}\Omega$
- 6.48 (a) $R_1 = 38.8 \text{ k}\Omega$, $R_2 = 35 \text{ k}\Omega$,
 $R_3 = 26.2 \text{ k}\Omega$, $R_D = 0.6 \text{ k}\Omega$,
 (b) $A_V = -5.36$
- 6.53 (a) $I_{DQ} = 1.42 \text{ mA}$, $V_{SDQ} = 2.9 \text{ V}$,
 (b) $A_V = 0.844$, $A_i = 4.18$,
 (c) 5.8 V peak-to-peak
- 7.8 (a) $|A_V| = 159$;
 (b) τ_S (open circuit) $= 5.31 \text{ ms}$, τ_P
 (short circuit) $= 0.332 \mu\text{s}$;
 (c) $C_C = 0.932 \mu\text{F}$, $C_L = 55.3 \text{ pF}$
- 7.11 (a) 959 Hz , (b) $|A_V| = 6.70$
- 7.13 (a) $R_S = 2.59 \text{ k}\Omega$, $R_D = 4.41 \text{ k}\Omega$,
 (c) $1.89 \mu\text{F}$
- 7.16 (a) $I_{DQ} = 1.8 \text{ mA}$, $V_{SDQ} = 5.68 \text{ V}$,
 $g_m = 2.68 \text{ mA/V}$, $r_o = \infty$
 (b) For C_{C1} , $\tau_{S1} = 2.28 \text{ ms}$; For C_{C2} ,
 $\tau_{S2} = 51.2 \text{ ms}$
 (c) C_{C2} dominates; $f_{3-\text{dB}} = 3.1 \text{ Hz}$
- 7.19 $C_C = 456 \mu\text{F}$
- 7.22 (a) $C_E = 57.2 \mu\text{F}$,
 (b) $f_B \approx 199.7 \text{ Hz}$, $f_A = 0.556 \text{ Hz}$
- 7.25 $C_L = 121 \text{ pF}$
- 7.31 $f_T = 511 \text{ MHz}$, $f_\beta = 4.26 \text{ MHz}$
- 7.33 (a) $f_\beta = 13.3 \text{ MHz}$, (b) $f = 199 \text{ MHz}$
- 7.37 $f_L = 540 \text{ Hz}$, $f_H = 344 \text{ kHz}$
- 7.41 (a) $r_S = 198 \Omega$, (b) 12%
- 7.44 (a) $C_n = 2.21 \text{ pF}$, $C_M = 27.7 \text{ pF}$,
 (b) $f_H = 3.06 \text{ MHz}$, $A_V = -19.5$
- 7.47 (a) $f_H = 10.4 \text{ MHz}$, (b) $C_M = 18.2 \text{ pF}$,
 (c) $A_V = -4.66$
- 7.50 $f_{P\mu} = 17.9 \text{ MHz}$, $A_V = 0.863$

Chapter 8

Chapter 7

- 7.1 (c) $v_o(t) = 1 - e^{-t/R_1 C_1}$
- 7.5 (a) $\tau_S = (R_i + R_P)C_S = 0.40 \text{ s}$,
 $\tau_P = (R_i || R_P)C_P = 0.375 \mu\text{s}$
 (b) $f_L = 0.398 \text{ Hz}$, $f_H = 424 \text{ kHz}$,
 $|T|_{\max} = 7.5 \text{ k}\Omega$

- 8.2 (a) $R_L = 7.2 \Omega$, $R_B = 1.12 \text{ k}\Omega$,
 (b) $V_P = 26 \text{ mV}$
- 8.5 (b) 9.38 , 30 , 39.4 , 10.8 , **7.16 W**,
 (c) Yes
- 8.9 $T_{\text{dev}} = 136^\circ\text{C}$, $T_{\text{case}} = 101^\circ\text{C}$, $T_{\text{sink}} = 85^\circ\text{C}$
- 8.11 $P_D = 10 \text{ W}$
- 8.13 (a) $I_Q = 9.8 \text{ mA}$, $R = 949 \Omega$,
 $i_{E1(\text{max})} = 19.6 \text{ mA}$,
 $i_{E1(\text{min})} = 0$, $i_L(\text{max}) = 9.8 \text{ mA}$,
 $i_L(\text{min}) = -9.8 \text{ mA}$,
 (b) **16.3%**

- 8.16 (a) $v_o(\max) = 8 \text{ V}$, $i_L = 1.6 \text{ mA}$,
 $v_I = 10 \text{ V}$,
(b) 62.7%
- 8.19 (a) $V_{BB} = 5 \text{ V}$, $P = 5 \text{ mW}$,
(b) $v_o(\max) = 8 \text{ V}$, $i_L = i_{Dn} = 8 \text{ mA}$,
 $i_{Dp} = 0$, $v_I = 9.5 \text{ V}$, $P_L = 64 \text{ mW}$,
 $P_{Mn} = 16 \text{ mW}$, $P_{Mp} = 0$
- 8.21 (a) $200 \mu\text{A}/\text{V}^2$
- 8.24 $\bar{P}_L(\max) = 112.5 \text{ mW}$, $R_1 = 40.4 \text{ k}\Omega$,
 $R_2 = 13.3 \text{ k}\Omega$
- 8.29 (a) Set $V_o = 0.9V_{CC} = aV_P$, then
 $a = 2.86$;
(b) $P_Q = 4.95 \text{ W}$
- 8.33 $R_i = 46.4 \text{ k}\Omega$

Chapter 9

- 9.2 (a) $A_v = -10$, $R_i = 10 \text{ k}\Omega$;
(b) $A_v = -5$, $R_i = 10 \text{ k}\Omega$;
(c) $A_v = -20$, $R_i = 5 \text{ k}\Omega$
- 9.5 $R_2 = 1 \text{ M}\Omega$, $R_1 = 33.3 \text{ k}\Omega$
- 9.7 (a) $v_O = -150 \sin \omega t (\text{mV})$;
(b) $i_2 = 10 \sin \omega t (\mu\text{A})$,
 $i_L = -37.5 \sin \omega t (\mu\text{A})$,
 $i_O = -47.5 \sin \omega t (\mu\text{A})$
- 9.11 (a) $450 \text{ k}\Omega$, (b) $4.95 \text{ M}\Omega$
- 9.15 (a) -1.996 V , (b) $+1.996 \text{ V}$
- 9.19 (a) $v_O = -2.667 \text{ V}$,
(b) $v_{I3} = 0.525 \text{ V}$
- 9.20 $R_1 = 20 \text{ k}\Omega$, $R_2 = 160 \text{ k}\Omega$, $R_F = 80 \text{ k}\Omega$
- 9.24 (a) $R_F = 10 \text{ k}\Omega$,
(b) $v_O = 0.3125 \text{ V}$, 4.6875 V
- 9.27 $R_1 = 8 \text{ k}\Omega$, $R_2 = 72 \text{ k}\Omega$
- 9.31 $A_v = 5$
- 9.34 $v_{O1} = -v_{O2} = \left(1 + \frac{R_2}{R_1}\right) \cdot v_I$
- 9.37 (b) $R_S \geq 1.1 \text{ k}\Omega$
- 9.40 $R_2 = R_3 = 1 \text{ k}\Omega$, Set $R_1 = R_F = 1 \text{ k}\Omega$
- 9.43 $v_{12} = 2.5 \text{ V}$

- 9.47 $R_{if} = 1.52 \text{ k}\Omega$, Potentiometer $\approx 300 \text{ k}\Omega$
- 9.50 (a) $f = 31.8 \text{ Hz}$, Phase $= -90^\circ$,
(b) $f = 15.9 \text{ Hz}$, 159 Hz
- 9.53 (a) $A_v = -\frac{R_2}{R_1} \cdot \frac{j\omega R_1 C_1}{1 + j\omega R_1 C_1}$,
(b) $A_v = -\frac{R_2}{R_1}$, (c) $f = \frac{1}{2\pi R_1 C_1}$

Chapter 10

- 10.2 $I_{C1} = I_{C2} = 962 \mu\text{A}$, $I_{B1} = I_{B2} = 19.2 \mu\text{A}$
- 10.5 $I_{REF} = 0.54 \text{ mA}$, $R_1 = 7.96 \text{ k}\Omega$
- 10.7 (a) $R_1 = 9.3 \text{ k}\Omega$, (b) $I_O = 2 \text{ mA}$,
(c) $R_{C2} = 4.65 \text{ k}\Omega$
- 10.11 (a) $I_2 = 1.0 \text{ mA}$, $I_3 = 1.5 \text{ mA}$;
(b) $I_1 = 0.25 \text{ mA}$, $I_3 = 0.75 \text{ mA}$;
(c) $I_1 = 0.167 \text{ mA}$, $I_2 = 0.333 \text{ mA}$
- 10.14 $I_{REF} = 0.500392 \text{ mA}$, $R_1 = 17.19 \text{ k}\Omega$
- 10.17 $I_{REF} = 1.00053 \text{ mA}$, $R_1 = 9.295 \text{ k}\Omega$
- 10.20 (a) 0.466 mA , (b) 400Ω
- 10.23 $R_O = 12.8 \text{ M}\Omega$, 0.936%
- 10.25 $V_{BE1} = 0.681 \text{ V}$, $I_{REF} = 0.482 \text{ mA}$,
 $I_O = 8.7 \mu\text{A}$, $V_{BE2} = 0.577 \text{ V}$
- 10.29 $R_{E2} = 10.17 \text{ k}\Omega$, $R_{E3} = 2.44 \text{ k}\Omega$,
 $R_1 = 18.6 \text{ k}\Omega$,
 $V_{BE2} = 0.598 \text{ V}$, $V_{BE3} = 0.6268 \text{ V}$
- 10.32 (a) $I_{O1} = 4.64 \text{ mA}$, $I_{O2} = 2.32 \text{ mA}$,
 $I_{O3} = 6.96 \text{ mA}$,
(b) $R_{C1} \approx 2 \text{ k}\Omega$, $R_{C2} \approx 4 \text{ k}\Omega$, $R_{C3} \approx 1.34 \text{ k}\Omega$
- 10.35 (a) $0.475 \leq I_O \leq 0.525 \text{ mA}$,
(b) $0.451 \leq I_O \leq 0.551 \text{ mA}$
- 10.38 $(W/L)_2 = 3.125$, $(W/L)_1 = 1.25$,
 $(W/L)_3 = 0.2$
- 10.41 $(W/L)_2 = 20$, $(W/L)_1 = 60$,
 $(W/L)_3 = 0.986$
- 10.44 $I_{REF} = I_O = 0.74 \text{ mA}$, $V_{DS2(\text{sat})} = 0.86 \text{ V}$
- 10.47 (a) $I_{REF} = 80 \mu\text{A}$, $I_O \cong 80 \mu\text{A}$;
(b) From a PSpice analysis,
 $\Delta I_O = 0.052 \mu\text{A}$

10.50 $I_{REF} = 89.5 \mu A$, $I_1 = 17.9 \mu A$,
 $I_2 = 112 \mu A$, $I_3 = 71.6 \mu A$, $I_4 = 358 \mu A$

10.52 (a) $i_D = 2.5 \text{ mA}$, (b) $i_D = 3 \text{ mA}$,
(c) $i_D = 3.5 \text{ mA}$

10.56 (a) $V_{BE} = 0.5208 \text{ V}$,
(b) $R_I = 8.96 \text{ k}\Omega$,
(c) $V_I = 4.462 \text{ V}$,
(d) $A_v = -1846$

10.60 $A_v = -4447$

Chapter 11

11.1 (a) $R_E = 2 \text{ k}\Omega$, $R_c = 4 \text{ k}\Omega$;
(c) $v_{CM}(\text{max}) = 4 \text{ V}$, $v_{CM}(\text{min}) = -8 \text{ V}$

11.5 (a) (i) 0 V , (ii) -0.1 V
(b) (i) 0.768 V , (ii) 0.758 V

11.8 (a) $R_E = 62 \text{ k}\Omega$,
(b) $A_d = 71.0$, $A_{cm} = -0.398$,
 $\text{CMMR}_{dB} = 45 \text{ dB}$
(c) $R_{id} = 70.4 \text{ k}\Omega$, $R_{icm} = 6.28 \text{ M}\Omega$

11.18 (a) $R_{id} = 46.8 \text{ k}\Omega$,
(b) $R_{icm} = 43.1 \text{ M}\Omega$

11.22 (a) $R_D = 47.5 \text{ k}\Omega$, $R_I = 73.75 \text{ k}\Omega$,
 $I_Q = I_1 = 240 \mu A$
(b) $\Delta I_Q \cong 13 \mu A$

11.25 (a) $v_d = 1 \text{ V}$, (b) $v_{d,\text{max}} = 1.58 \text{ V}$

11.30 $v_{cm}(\text{max}) = 6 \text{ V}$

11.36 (a) $I_Q = 1 \text{ mA}$, $R_D = 6 \text{ k}\Omega$,
(b) $g_f(\text{max}) = 0.25 \text{ mA/V}$,
(c) $A_d = 1.5$

11.41 (a) $A_d \approx 2307$, (b) $R_L = 150 \text{ k}\Omega$

11.44 (a) $I_O = 2 \mu A$, (b) $A_d = 1923$,
(c) $A_d = 641$

11.48 (a) $V_{DS3} = V_{DS4} = 2 \text{ V}$,
 $V_{DS1} = V_{DS2} = 10 \text{ V}$,
(b) $A_d = 80$, (c) $R_o = 400 \text{ k}\Omega$

11.56 (a) $A_d = 88.9$

11.62 $R_i \cong 1.05 \text{ M}\Omega$, $R_o = 0.472 \text{ k}\Omega$,
 $A_v = -438$

11.66 (a) $R_{C1} = 80 \text{ k}\Omega$, $R_{C2} = 20 \text{ k}\Omega$;
(b) $A_{d1} = -69.6$, $A_d = -5352$

Chapter 12

12.1 (a) 1.249×10^{-2} ,
(b) -0.016% , 79.987 ,
(c) $\beta = 1.15 \times 10^{-2}$, -1.6% , 78.72

12.4 $A = 4999$

12.6 (a) $f_H = 8 \text{ kHz}$, (b) $f_H = 40 \text{ kHz}$

12.8 1000

12.11 (a) $R_i(\text{max}) = 10^5 \text{ k}\Omega$, $R_i(\text{min}) = 1 \text{ }\Omega$
(b) $R_o(\text{max}) = 10^4 \text{ k}\Omega$,
 $R_o(\text{min}) = 0.1 \text{ }\Omega$

12.14 $R_{if} \cong 500 \text{ M}\Omega$, $R_{of} = 0.0219 \text{ }\Omega$

12.18 $R_{if} = 10^6 \text{ k}\Omega$, $R_{of} = 5.04 \text{ M}\Omega$

12.22 (a) $I_{C1} = I_{C2} = 0.5 \text{ mA}$,
 $I_{C3} = 2 \text{ mA}$, $v_O = 0$;
(b) $A_{if} = 5.68$

12.26 $A_{if} = 45.4$

12.30 (a) $r_{\pi 1} = 15.8 \text{ k}\Omega$, $g_{m1} = 7.62 \text{ mA/V}$,
 $r_{\pi 2} = 2.28 \text{ k}\Omega$, $g_{m2} = 52.7 \text{ mA/V}$
(b) $A_{if} = 8.63$; (c) $R_{if} = 45.1 \text{ }\Omega$

12.34 $A_{if} = 5.33$

12.38 $A_{if} = 98.06 \text{ mA/V}$

12.41 (a) $A_v = -3.41$,
(b) $A_{if} = -85.0 \text{ V/mA}$,
(c) $R_{if} = 14.9 \text{ k}\Omega$,
(d) $R_{of} = 4.88 \text{ k}\Omega$

12.45 $R_F = 27.2 \text{ k}\Omega$

12.49 $T = 84.45$

12.51 (a) $f_{180} \cong 1.05 \times 10^4 \text{ Hz}$,
(b) $\beta = 4.42 \times 10^{-4}$

12.55 (c) For $\beta = 0.005$, system is stable.
Phase margin = 14° ;
For $\beta = 0.05$, system is unstable.

12.60 $\beta = 0.01428$

12.65 $f_{PD} = 555 \text{ Hz}$

Chapter 13

13.5 56.4 V

13.9 $I_{C2} = 10.28\text{ }\mu\text{A}, I_{C9} = 17.13\text{ }\mu\text{A},$
 $I_{B9} = 1.713\text{ }\mu\text{A}, I_{B4} = 0.9345\text{ }\mu\text{A},$
 $I_{C4} = 9.345\text{ }\mu\text{A}$

13.12 $I_{C14} = 21.8\text{ mA}, I_{C15} = 0.071\text{ mA}$

13.14 $R_1 = 30.32\text{ k}\Omega, R_2 = 33.96\text{ k}\Omega$

13.18 $R_{id} = 2.095\text{ M}\Omega$

13.22 (a) $I_{REF} = I_Q = I_{D7} = 89.2\text{ }\mu\text{A},$
(b) $A_d = 141, A_{v2} = 141, A_v = 19,881$

13.26 $R_o = 1.26\text{ M}\Omega$

13.38 $-15 \leq v_{CM} \leq 11.6\text{ V}$

13.41 $A_d = 10.38, |A_{v2}| = 1917, |A| = 19,895$

13.43 $I_{DSS} = 0.8\text{ mA}$

Chapter 14

14.1 (a) $A_{CL} = -4.52, R_{if} = 90.8\text{ }\Omega$
(b) $A_{CL} = -4.92, R_{if} = 98.9\text{ }\Omega$
(c) $A_{CL} = -4.965, R_{if} = 99.8\text{ }\Omega$

14.5 (a) $A_v \approx 1, (b) R_{of} = 0.02\text{ }\Omega$

14.8 (a) $R_{if} = 99.1\text{ }\Omega, (b) R_{of} = 18.4\text{ }\Omega,$
(c) $A_{CL} = 0.65, (d) 0.65$

14.11 $f_{3-\text{dB}} = 40\text{ Hz}, f_T = 2\text{ MHz}$

14.14 $f_{\max} = 159\text{ kHz}$

14.18 6.37 V

14.22 10^3 s

14.26 $i_{C1}/i_{C2} = 1.0155$

14.31 (a) $v_{O1} = v_{O2} = 0.5\text{ V}, v_{O3} = -0.3\text{ V},$
(b) $R_A = 8.33\text{ k}\Omega, R_B = 10\text{ k}\Omega,$
(c) $v_{O1} = v_{O2} = 0.1\text{ V}, v_{O3} = -0.14\text{ V}$

14.34 (a) $R_2 = 22.48\text{ M}\Omega, (b) R_1 = 6\text{ k}\Omega$

14.37 For (a) $v_O = 9\text{ mV},$
for (b) $v_O = -1.0815\text{ V}$

14.40 (a) Circuit a: $v_O = 0, \text{ Circuit b: } v_O = -0.975\text{ V}$

(b) Circuit a: $v_O = -0.010\text{ V}, \text{ Circuit b: } v_O = -1.18\text{ V}$

(c) Circuit a: $I_B \rightarrow v_O = 0, I_{OS} \rightarrow v_O = 0.0125\text{ V}$
Circuit b: $I_B \rightarrow v_O = -1.365\text{ V}, I_{OS} \rightarrow v_O = -1.62\text{ V}$

14.42 $\text{CMRR}_{\text{dB}} = 37.5\text{ dB}$

Chapter 15

15.6 $N = 5$

15.10 (b) $|A_v|_{\max} = 28.3, f_o = 5.305\text{ kHz},$
 $f_1 = 5.315\text{ kHz}, f_2 = 5.296\text{ kHz}$

15.13 (b) $R_2 = 524\text{ k}\Omega, C_1 = 0.0732\text{ }\mu\text{F},$
 $C_2 = 66.3\text{ pF}$

15.15 (a) $10\text{ M}\Omega, (b) 1\text{ M}\Omega, (c) 333\text{ k}\Omega$

15.18 (a) $\tau = 60\text{ }\mu\text{s}, (b) \Delta v_O = 0.167\text{ V},$
(c) $N = 78$

15.21 $R = 8.12\text{ k}\Omega, R_2 = 236\text{ k}\Omega$

15.25 (a) $f_o = \frac{1}{2\pi\sqrt{R_AR_BR_AC_AC_B}}$,

(b) $\frac{R_2}{R_1} = \frac{R_A}{R_B} + \frac{C_B}{C_A}$

15.29 $f_o = \frac{1}{2\pi\sqrt{\frac{C_1+C_2}{C_1C_2L}}}, \frac{C_1}{C_2} = g_m R_L$

15.34 $V_{REF} = -5\text{ V}, R_F = 10\text{ k}\Omega,$
 $R_{VAR} = 40\text{ k}\Omega$

15.36 (a) $V_{TH} = 2\text{ V}, V_{TL} = -2\text{ V}$

15.40 (b) $R_2 = 190\text{ k}\Omega, V_{REF} = 1.579\text{ V}$

15.42 (a) $R_2 = 12.6\text{ k}\Omega, (b) R = 3.02\text{ k}\Omega$

15.47 (b) Duty cycle = 50%, $f_o = 257\text{ Hz}$

15.52 $T = 3.80\text{ ms}, \text{ recovery time} \approx 2\text{ ms}$

15.56 $627\text{ Hz} \leq f \leq 4.81\text{ kHz},$
 $52.2 \leq \text{d.c.} \leq 66.7\%$

15.60 $\frac{R_2}{R_1} = 14, \frac{R_4}{R_3} = 15, \text{ Bias voltage} =$
 $\pm 12\text{ V}, I_P = 2\text{ A},$
Peak output voltage = $\pm 10\text{ V}$

Chapter 16

- 16.1 (a) $V_{SB} = 1\text{ V} \Rightarrow \Delta V_{TN} = 0.315\text{ V}$,
 $V_{SB} = 2\text{ V} \Rightarrow \Delta V_{TN} = 0.544\text{ V}$
(b) $I_D = 0.578, 0.384, 0.267\text{ mA}$
- 16.5 $v_u = 4.67\text{ V}$, $v_{O_L} = 2.67\text{ V}$, $v_O = 1.09\text{ V}$
- 16.8 5.79
- 16.11 $V_{TNE} = -2.88\text{ V}$
- 16.14 (a) (i) 0, (ii) 1.16 mW;
(b) (i) 0, (ii) 825 μW ;
(c) (i) 0, (ii) 200 μW
- 16.17 (a) (i) 4.2 V, (ii) 3.4 V
- 16.20 (a) 1.82;
(b) $(W/L)_L = 0.444$,
 $(W/L)_D = 0.808$;
(c) 0.0369 V
- 16.24 $\overline{(B \cdot C) + A}$
- 16.28 (a) $V_B = 2.5\text{ V}$, $V_{ONL} = 1.7\text{ V}$,
 $V_{OP_L} = 3.3\text{ V}$;
(c) 4.64 V, 0.356 V
- 16.33 (a) 144.5 μA , (b) 99.4 μA
- 16.37 $V_{IL} = 4.125\text{ V}$, $V_{OHU} = 9.125\text{ V}$,
 $V_{IH} = 5.875\text{ V}$, $V_{OLU} = 0.875\text{ V}$
 $NM_L = 3.25\text{ V}$, $NM_H = 3.25\text{ V}$
- 16.39 (a) 2.5 V, (b) $\left(\frac{W}{L}\right)_n = 4.5\left(\frac{W}{L}\right)_p$,
(c) 1.65 V
- 16.43 $(A \text{ OR } B) \text{ AND } C$
- 16.46 (b) $v_{O2} = (v_A \text{ OR } v_B) \text{ AND } v_C$
- 16.50 6.25 ms
- 16.55 Exclusive-OR function
- 16.67 (a) $(W/L) = 0.329$;
(b) 32.8 mA, 65.6 mW

Chapter 17

- 17.1 (a) $i_E = 0.56\text{ mA}$, $v_{O1} = 3.5\text{ V}$,
 $v_{O2} = 2.38\text{ V}$
(b) $i_E = 0.76\text{ mA}$, $v_{O2} = 3.5\text{ V}$
(e) For $v_{O1} = 2.38\text{ V}$, $R_{C1} = 1.47\text{ k}\Omega$

- 17.4 $R_5 = 2.8\text{ k}\Omega$, $R_E = 2.1\text{ k}\Omega$, $R_2 = 2.1\text{ k}\Omega$,
 $R_1 = 0.5\text{ k}\Omega$, $R_3 = 1.1\text{ k}\Omega$,
 $R_4 = 0.767\text{ k}\Omega$,
 $R_{C2} = 1\text{ k}\Omega$, $R_{C1} = 0.808\text{ k}\Omega$
- 17.8 (a) AND logic function;
(b) Logic 0 = 0 V, Logic 1 = 1.8 V;
(c) $i_{E1} = 1.65\text{ mA}$, $i_{C3} = 0$,
 $i_{C2} = i_{E3} = 3\text{ mA}$, $V_2 = 0$
(f) $i_{E1} = 0.962\text{ mA}$, $i_{C2} = 0$,
 $i_{C3} = i_{E2} = 2.25\text{ mA}$, $V_2 = 1.8\text{ V}$
- 17.10 (a) Logic 1 = +0.2 V, Logic 0 = -0.2 V,
(b) $R_E = 3\text{ k}\Omega$, (c) $R_1 = 1\text{ k}\Omega$,
(d) $i_{R2} = 0.4\text{ mA}$, $i_{D2} = 0.467\text{ mA}$,
(e) 10.98 mW
- 17.13 (a) Logic 1 = 0 V, Logic 0 = -0.4 V,
(b) $v_{O1} : A + B$, $v_{O2} : C + D$,
 $v_{O3} : (A + B) \cdot (C + D)$
- 17.15 (a) (i) $v^1 = 0.8\text{ V}$, $i_1 = 0.525\text{ mA}$,
 $i_3 = i_4 = 0$, $v_O = 5\text{ V}$
(ii) $v^1 = 2.2\text{ V}$, $i_1 = 0.35\text{ mA}$,
 $i_3 = 2.04\text{ mA}$, $i_4 = 0.297\text{ mA}$
(b) 7, (c) 5
- 17.18 (a) (i) $i_1 = 0.683\text{ mA}$,
 $i_{B2} = i_2 = i_4 = i_{B3} = i_3 = 0$,
(ii) $i_1 = i_{B2} = 0.45\text{ mA}$,
 $i_2 = 2.05\text{ mA}$, $i_4 = 0.533\text{ mA}$,
 $i_{B3} = 1.97\text{ mA}$, $i_3 = 2.23\text{ mA}$
- 17.22 (a) $i_{B1} = 1.05\text{ mA}$, other currents = 0,
(b) $i_{B1} = 0.926\text{ mA}$, $i_{B2} = 1.59\text{ mA}$,
 $i_{C2} = 2.05\text{ mA}$,
 $i_{B3} = 2.64\text{ mA}$, $i_{C3} = 7.29\text{ mA}$
- 17.26 (a) $v_{B1} = 1.1\text{ V}$, $i_{B1} = 1.39\text{ mA}$,
 $v_{B2} = 0.8\text{ V}$, $i_{B4} = 0.0394\text{ mA}$,
 $i_{C4} = 1.18\text{ mA}$, $v_{B4} = 4.97\text{ V}$,
all other currents = 0
(b) $v_{B1} = 1.7\text{ V}$, $v_{B2} = 1.4\text{ V}$,
 $v_{BO} = 0.7\text{ V}$, $v_{C2} = 1.1\text{ V}$,
 $i_{B1} = 1.18\text{ mA}$, $i_{B2} = 1.42\text{ mA}$,
 $i_{B4} = 0.00369\text{ mA}$,
 $i_{C2} = 5.13\text{ mA}$, $i_{BO} = 6.55\text{ mA}$
- 17.29 (a) $i_{E1} = 0.0975\text{ mA}$, $P = 0.4875\text{ mW}$;
(b) $P = 1.98\text{ mW}$;
(c) $i_{Sc} \cong 78\text{ mA}$

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TN710 FN34
Electronic circuit analysis and
design = 电子电路分析与设计
E0522324W